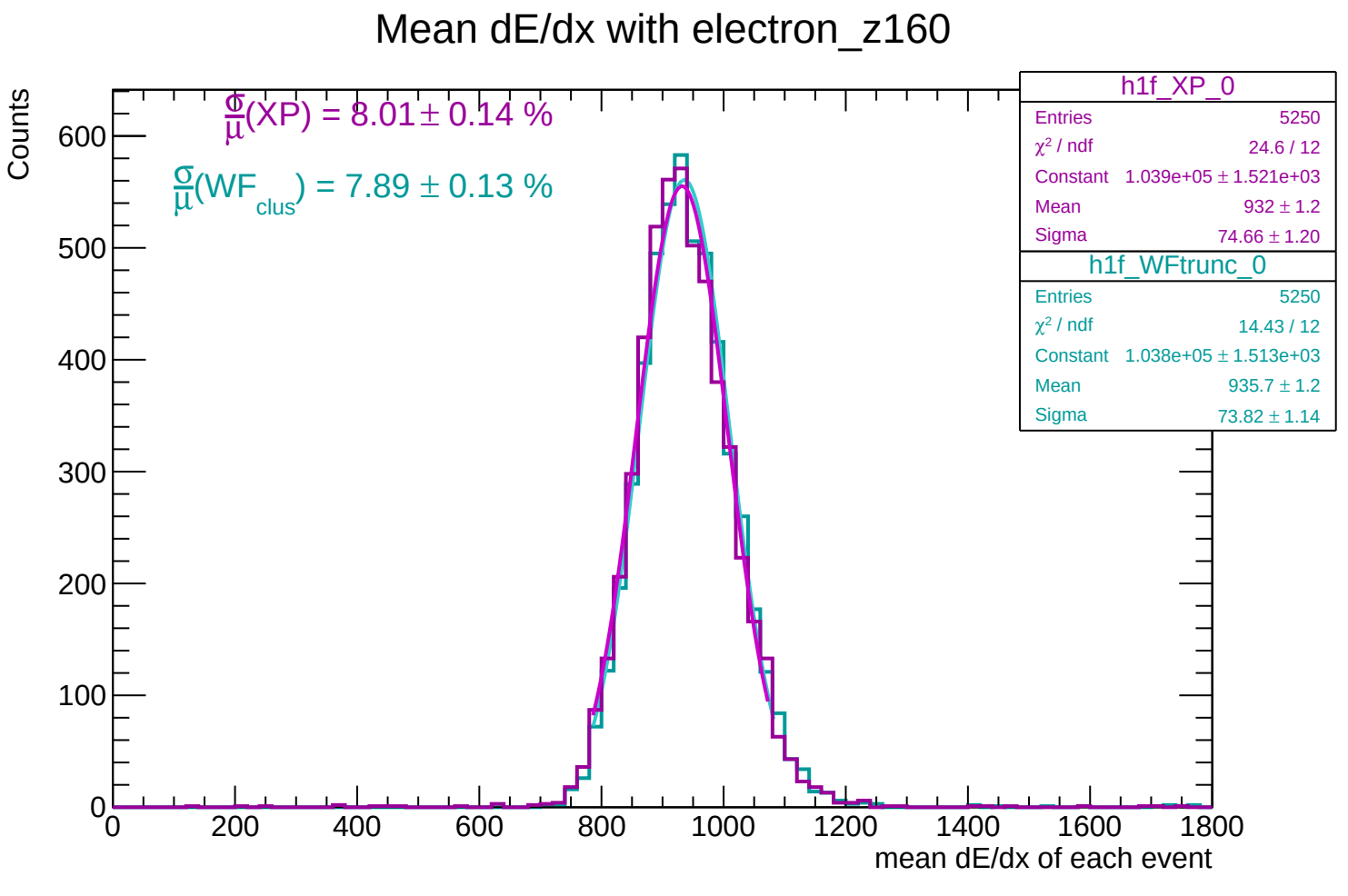
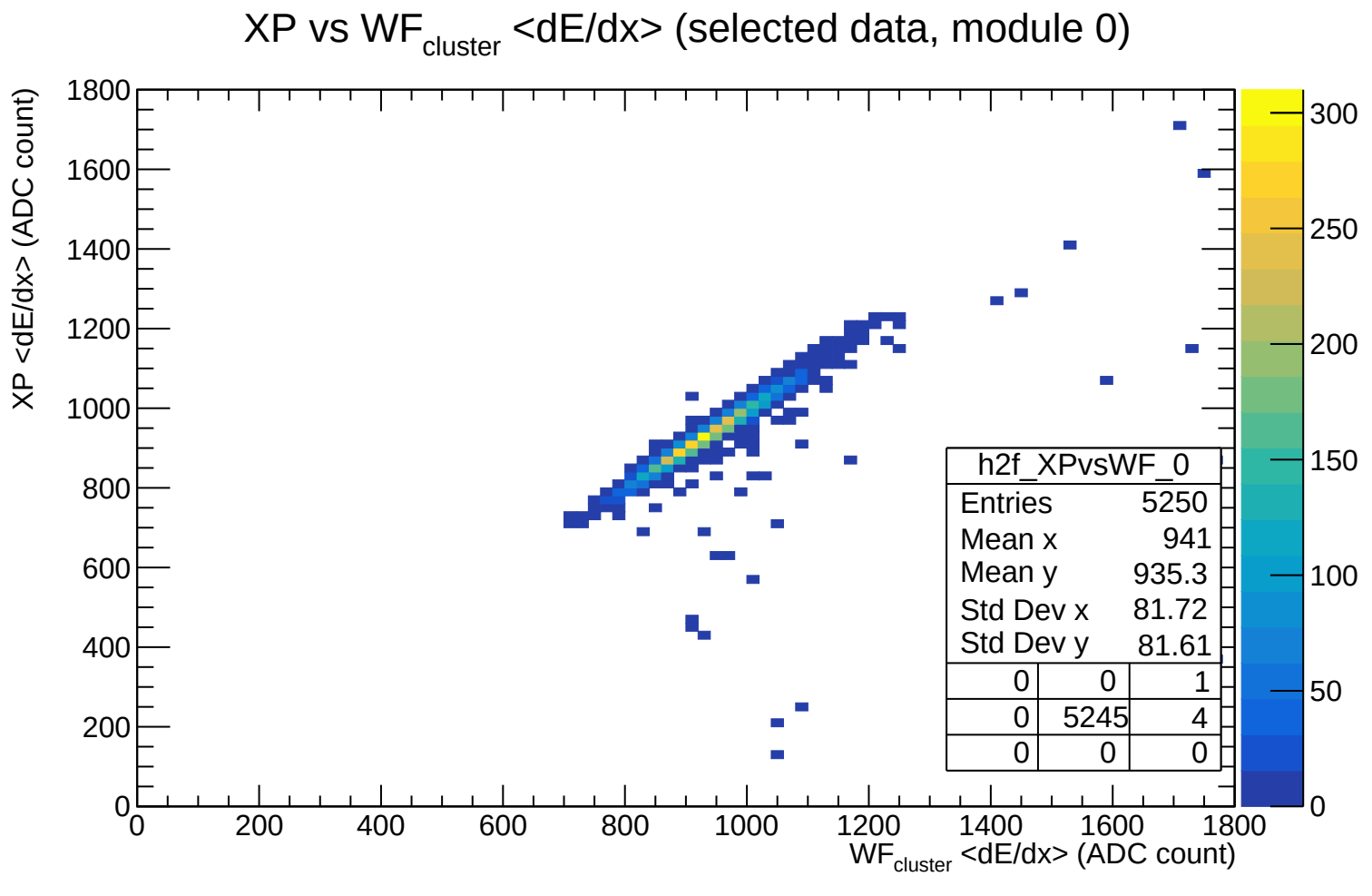
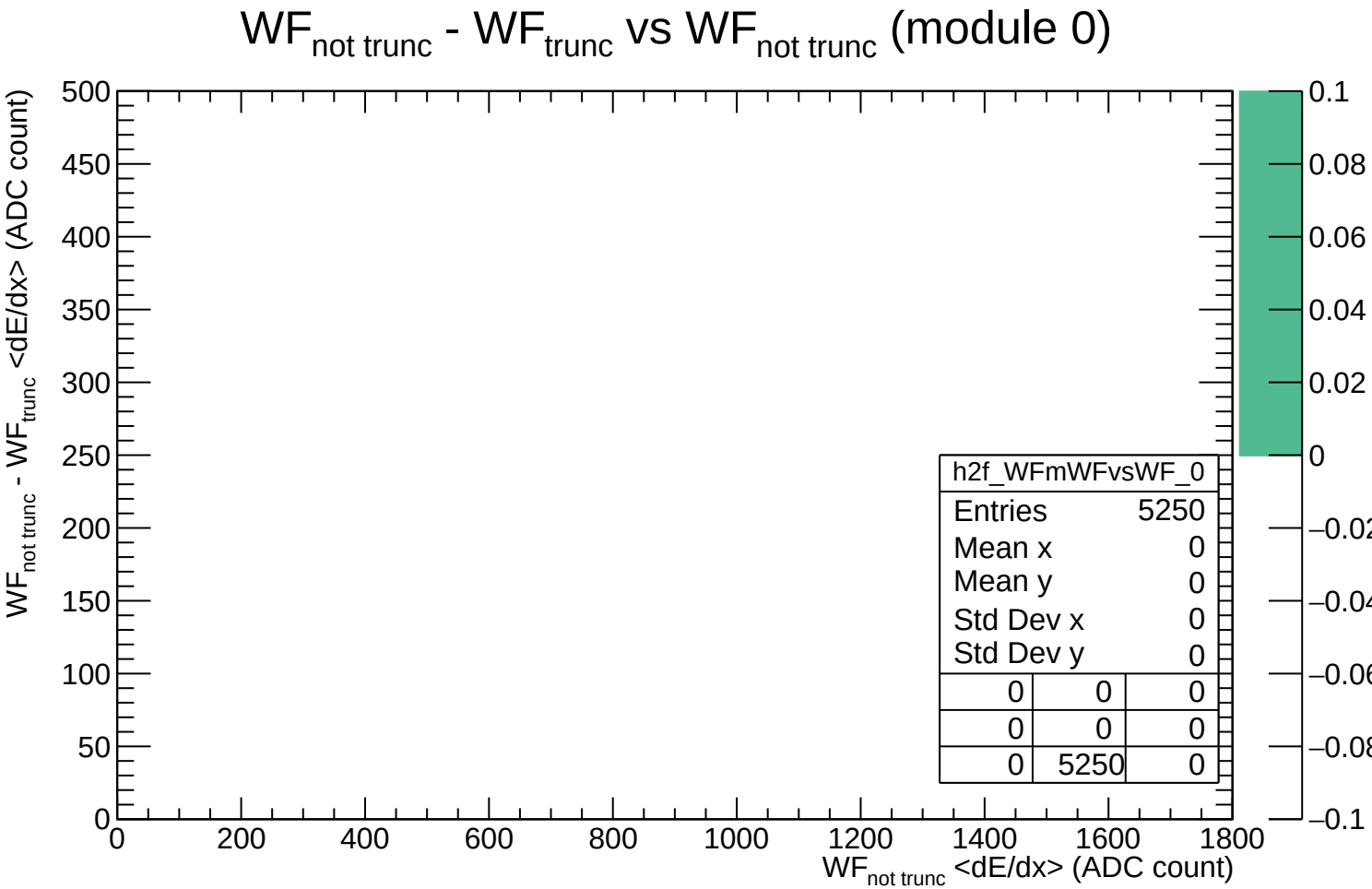

Mean dE/dx with electron_z160
Counts
mean dE/dx of each event
σ/μ(XP) = 8.01 ± 0.14 %
σ/μ(WF clus) = 7.89 ± 0.13 %
h1f_XP_0
Entries 5250
χ² / ndf 24.6 / 12
Constant 1.039e+05 ± 1.521e+03
Mean 932 ± 1.2
Sigma 74.66 ± 1.20
h1f_WFtrunc_0
Entries 5250
χ² / ndf 14.43 / 12
Constant 1.038e+05 ± 1.513e+03
Mean 935.7 ± 1.2
Sigma 73.82 ± 1.14
0
100
200
300
400
500
600
0
200
400
600
800
1000
1200
1400
1600
1800


XP vs WF$_{cluster}$ <dE/dx> (selected data, module 0)
XP <dE/dx> (ADC count)
WF$_{cluster}$ <dE/dx> (ADC count)
h2f_XPvsWF_0
Entries 5250
Mean x 941
Mean y 935.3
Std Dev x 81.72
Std Dev y 81.61
0 0 1
0 5245 4
0 0 0


WF not trunc - WF trunc vs WF not trunc (module 0)
WF not trunc - WF trunc <dE/dx> (ADC count)
WF not trunc <dE/dx> (ADC count)
h2f_WFmWFvsWF_0
Entries 5250
Mean x 0
Mean y 0
Std Dev x 0
Std Dev y 0
0 0 0
0 0 0
0 5250 0